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Sommario/riassunto

This book, authored by Thien-Phap Nguyen, explores the topic of defects in organic semiconductors and electronic devices. It provides a comprehensive overview of organic materials, focusing on their structure, doping, and the architectures of various organic electronic devices such as diodes, solar cells, and transistors. The book delves into the nature of defects within these materials, examining their impact on carrier transport, trapping mechanisms, and optical properties. It also discusses various techniques for studying these defects, including electron spin resonance, fluorescence spectroscopy, and electrical measurement techniques. The work is intended for researchers, engineers, and professionals in the field of organic electronics, offering insights into the challenges and advancements in the study and application of organic materials in electronic devices.
